

# PNP Transistor Bare Die – TIP127

Rev 1.0 19/12/23

#### Bipolar Darlington Power Transistor in bare die form

Complement to NPN TIP122

#### Features:

- Collector current up to 5A
- Low V<sub>CE</sub>(sat)
- Very high h<sub>FE</sub>
- Solderable back metal
- High Reliability tested grades for Military + Space

### Ordering Information:

The following part suffixes apply:

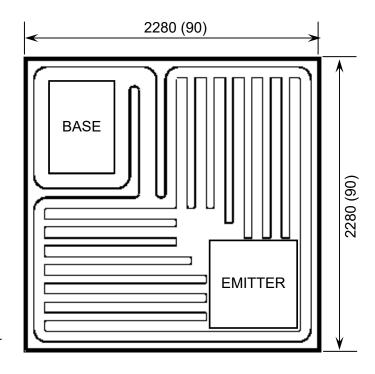
- No suffix Commercial grade die
- "H" Hi-rel grade die + MIL-STD-38534 Class H LAT
- "K" Hi-rel grade die + MIL-STD-38534 Class K LAT.

LAT = Lot acceptance Test.

For information on Hi-Rel LAT flows please see below.

www.siliconsupplies.com\bare-die-lot-qualification

## Die Dimensions in µm (mils)



**DIE BACK = COLLECTOR** 

### **Supply Formats:**

- Default Die in Waffle Pack (100 per tray capacity)
- Sawn Wafer on Tape Specific request
- Unsawn Wafer Specific request
- With additional electrical selection Specific request
- Sawn as pairs or adjacent pair pick Specific request

# **Mechanical Specification**

2280 x 2280	μm	
89.76 x 89.76	mils	
680 x 680	µm	
26.77 x 30.95	mils	
446 x 606	μm	
17.56 x 25.71	mils	
260 (±25)	μm	
10.2 (±1)	mils	
Al		
Ti/Ni/Ag		
	89.76 x 89.76 680 x 680 26.77 x 30.95 446 x 606 17.56 x 25.71 260 (±25) 10.2 (±1) Al	





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## Absolute Maximum Ratings T<sub>A</sub> = 25°C unless otherwise stated

PARAMETER	SYMBOL	VALUE	UNIT
Collector-Base Voltage	V <sub>CBO</sub>	100	V
Collector-Emitter Voltage	V <sub>CEO</sub>	100	V
Emitter-Base Voltage	V <sub>EBO</sub>	5	V
Collector Current - Continuous	I <sub>C</sub>	5	A
Collector Current – Peak (t <sub>P</sub> < 5ms)	I <sub>CM</sub>	8	,,
Base Current	I <sub>B</sub>	0.12	A
Junction Temperature	TJ	150	°C
Storage Temperature	T <sub>stg</sub>	-65 to 150	°C

#### Electrical Characteristics T<sub>A</sub> = 25°C unless otherwise stated

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNIT
OFF CHARACTERISTICS						
Collector-Base Breakdown Voltage	V <sub>(BR)CBO</sub>	I <sub>E</sub> = 0	100	-	-	V
Collector-Emitter Sustaining Voltage <sup>1</sup>	V <sub>CEO(SUS)</sub>	$I_B = 0, I_C = 30 \text{mA}$	100	-	-	V
Emitter-Base Breakdown Voltage	V <sub>(BR)EBO</sub>	I <sub>C</sub> = 0	5	-	-	V
Collector Cut-off Current	I <sub>CEO</sub>	V <sub>CE</sub> = 50V, I <sub>B</sub> = 0	-	-	0.5	mA
Emitter Cut-off Current	I <sub>EBO</sub>	$V_{EB} = 5V, I_{C} = 0$	-	-	2	mA
Collector Cut-off Current	I <sub>CBO</sub>	$V_{CB} = 100V, I_{E} = 0$	-	-	0.2	mA
ON CHARACTERISTICS						
Forward-Current Transfer Ratio <sup>1</sup>	h <sub>FF</sub>	$I_C = 0.5A, V_{CE} = 3V$	1000	-	-	-
	I I FE	$I_C = 3.0A, V_{CE} = 3V$	1000	-	-	-
Collector-Emitter Saturation Voltage <sup>1</sup>	V <sub>CE(sat)</sub>	$I_C = 3A, I_B = 12mA$	-	-	2	V
	V CE(sat)	$I_C = 5A, I_B = 20mA$	-	-	4	V
Base-Emitter Saturation Voltage <sup>1</sup>	V <sub>BE(on)</sub>	$I_{C} = 3A, V_{CE} = 3V$	-	-	2.5	V
SMALL SIGNAL CHARACTERISTICS <sup>2</sup>						
Small-Signal Current Gain	h <sub>fe</sub>	V <sub>CE</sub> = 4V, I <sub>C</sub> = 3A, f = 1MHz	4	-	-	-
Output Capacitance	C <sub>ob</sub>	$V_{CB} = 10V$ , $I_E = 0$ , $f = 0.1MHz$	-	-	300	pF

<sup>1.</sup> Pulsed duration = 300 ms, duty cycle ≥1.5%

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<sup>2.</sup> Not production testing in die form, characterized by chip design and package verification